

Substitute Form PTO-1449 (Modified) Information Disclosure Statement by Applicant (Use several sheets if necessary) (37 CFR §1.98(b))	U.S. Department of Commerce Patent and Trademark Office		Attorney's Docket No. 11540-004001	Application No.
	Applicant Henry A. Hill			
	Filing Date July 27, 2001		Group Art Unit	

 1-328 U.S. PTO
09/01/2001

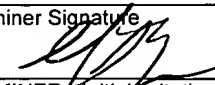
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Examiner Initial	Desig. ID	Patent Number	Issue Date	Patentee	Class	Subclass	Filing Date If Appropriate
SY	AA	4,659,429	04/1987	Isaacson et al.			
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Foreign Patent Documents or Published Foreign Patent Applications

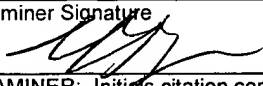
Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
SY	AX	0 409 468 A2	01/1991	Europe				

Examiner Signature 	Date Considered 12/1/02
EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	

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	Applicant Henry A. Hill		
	Filing Date July 27, 2001	Group Art Unit	

Foreign Patent Documents or Published Foreign Patent Applications								
Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
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	AZ	5-174410	05/1993	Japan				✓
	AAA	5-73980	05/1993	Japan				✓

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Examiner Initial	Desig. ID	Document
SV	ABB	Bauer et al., "Magnetic Domain Imaging with a Scanning Near-Field Optical Microscope Using a Modified Sagnac Interferometer," <u>Journal of Microscopy</u> , 194:2/3:507-511, May/June 1999. ✓
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SV	AGG	Fischer, "Optical Characteristics of 0.1 μ m Circular Apertures in a Metal Film as Light Sources for Scanning Ultramicroscopy," <u>J. Vac. Sci. Technol. B</u> 3:1:386-390, Jan/Feb 1985. ✓
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SV	AJJ	Meixner et. al., "Direct Measurement of Standing Evanescent Waves with a Photon-Scanning Tunneling Microscope," <u>APPLIED OPTICS</u> , 33:34:7995-8000, December 1, 1994. ✓
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SV	ALL	Guerra, "Photon Tunneling Microscopy," <u>APPLIED OPTICS</u> , 29:26:3741-3752, September 10, 1990. ✓

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Substitute Form PTO-1449 (Modified) OCT 21 2002 Information Disclosure Statement by Applicant (Use several sheets if necessary) (37 CFR §1.98(b))	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 11540-005001	Application No. 09/917,400
	Applicant Henry A. Hill		
	Filing Date July 27, 2001	Group Art Unit 2881	

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	AK						

Foreign Patent Documents or Published Foreign Patent Applications

Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
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SK	AM	WO99/63300	12/1999	PCT International				
	AN							
	AO							
	AP							

Other Documents (include Author, Title, Date, and Place of Publication)

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	AR	
	AS	
	AT	

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